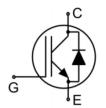


### **Main Product Characteristics:**

Vces	1250V		
lc	80A		
V <sub>CE(sat)</sub>	1.75V		





TO - 247Plus-3L

Schematic Diagram

#### **Features and Benefits:**

- Trench FS technology offering
- High speed switching
- Low gate charge and V<sub>CE(sat)</sub>
- High ruggedness, temperature stable behavior
- Maximum junction temperature 175°C



## **Applications:**

- Solar inverters
- Uninterruptible power supplies
- Motor drives
- Air condition

# **Absolute Max Rating:**

Symbol	Parameter	Value	Units
V <sub>CES</sub>	Collector-Emitter Voltage	1250	V
$V_{GES}$	Gate- Emitter Voltage	±30	V
1	Collector Current	160	
Ic	Collector Current @T <sub>C</sub> = 100 °C	80	A
I <sub>Cpuls</sub>	Pulsed Collector Current, tp limited by Tjmax	320	
-	Turn off safe operating area, V <sub>CE</sub> =650V, T <sub>J</sub> =175°C	320	
	Diode Continuous Forward Current @Tc = 25 °C	160	
lF	Diode Continuous Forward Current @Tc = 100 °C	80	Α
IFM	Diode Maximum Forward Current	320	
P <sub>D</sub>	Power Dissipation @ T <sub>C</sub> = 25°C	833	W
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +175	°C
T∟	Maximum Temperature for Soldering	260	°C

Version: 1.1





### **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
R <sub>0JC</sub>	Thermal Resistance, Junction-to-case for IGBT	_	0.18	°C/W
	Thermal Resistance, Junction-to-case for Diode	_	0.43	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-ambient	_	40	°C/W

## Electrical Characteristics @T<sub>A</sub>=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V(BR)CES	Collector-Emitter Breakdown Voltage	1250	_	_	V	Vge=0V,Ice=1mA	
V	Callegian Fraitten Catamatian Valtage		4.75	0.4	V	Ic=80A ,VgE=15V	
VCE(sat)	Collector-Emitter Saturation Voltage	_	1.75	2.1	V	@T <sub>J</sub> =25°C	
VGE(th)	Gate Threshold Voltage	4.5	_	6.5	V	Ic=250µA,VcE=VgE	
Ices	Collector-Emitter Leakage Current	_	_	1	μA	VgE =0V,VcE=1200V	
Iges	Cata to Emitter Payerna Lankaga	_	_	100	nA	VGE=30V,VCE=0V	
IGES	Gate to Emitter Reverse Leakage	_	_	-100	I IIA	VGE=-30V, VCE =0V	
Cies	Input capacitance	_	11810	_		V <sub>GS</sub> =0V	
Coes	Output capacitance	_	164	_	pF	V <sub>DS</sub> =100V	
Cres	Reverse transfer capacitance	_	108	_		f = 1MHz	
t <sub>d(on)</sub>	Turn-on delay time	_	65	_			
t <sub>r</sub>	Rise time	_	39	_	,,,	Vcc=600V,Ic=80A,	
t <sub>d(off)</sub>	Turn-Off delay time	_	593	_	ns	$V_{GE}=0/15V, R_g=10\Omega,$	
t <sub>f</sub>	Fall time	_	54	_			
Eon	Turn-On Switching Loss	_	7.89	_		\/ C00\/ I- 00A	
Eoff	Turn-Off Switching Loss	_	5.04	_	mJ	Vcc=600V,Ic=80A,	
Ets	Total Switching Loss	_	12.93	_		Vge=0/15V, $R_g=10\Omega$ ,	
Qg	Total Gate Charge	_	670	_		\/aa 060\/ la 90A	
Qge	Gate to Emitter Charge	_	108	_	nC	Vcc=960V, Ic=80A,	
Qgc	Gate to Collector Charge	_	255	_		VGE=10V	
	Short circuit collector current					V <sub>GE</sub> =15V,V <sub>CC</sub> ≤600V,	
Ic(sc)	Max.1000 short circuits	_	740	_	Α	V <sub>GE</sub> =15V,V <sub>CC</sub> ≪600V, t <sub>sc</sub> ≪13μs	
	Time between short circuits: ≥1.0s					isc≪ i oµo	

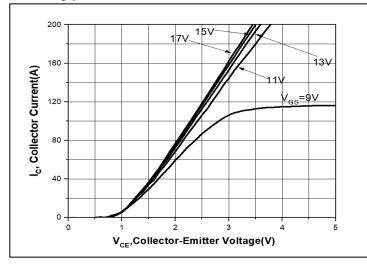
# Electrical Characteristics of the Diode@TA=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
VFM	Diode Forward Voltage	_	2.15	4	V	I=80A
t <sub>rr</sub>	Reverse Recovery Time	_	538	_	ns	
Qrr	Reverse Recovery Charge	_	4.81	_	μC	T <sub>J</sub> =25°C, I <sub>F</sub> =80A,V <sub>R</sub> =600V
lan	Diode Peak Reverse Recovery		22		^	V <sub>GE</sub> =0/15V
IRRM	Current	_	23	_	A	





## **Typical Electrical and Thermal Characteristics**



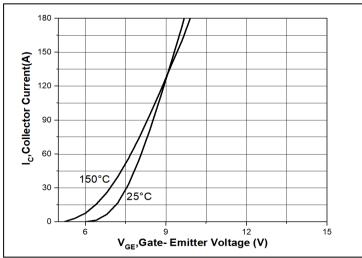
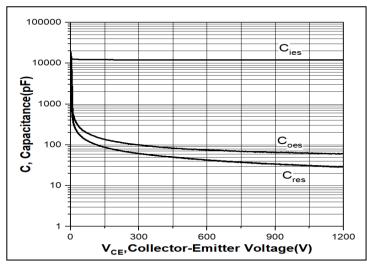


Figure 1. Typical Output Characteristics

Figure 2. Typical Transfer Characteristics



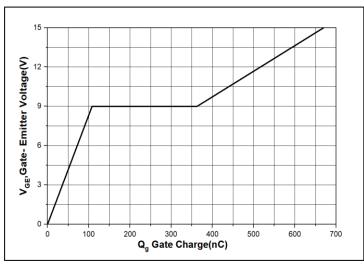


Figure 3. Typical Capacitance

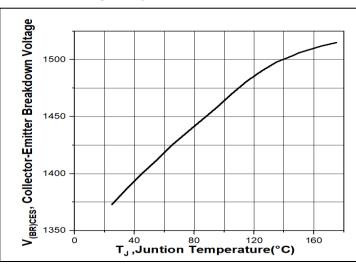


Figure 4. Typical Gate Charge

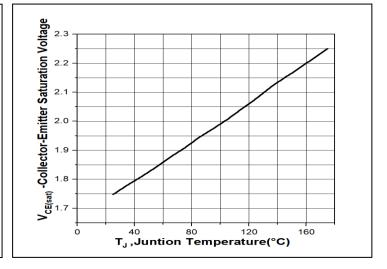


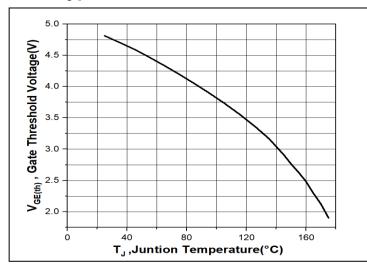
Figure 5. Collector-Emitter Breakdown Voltage vs. Temperature

Figure 6. Collector-Emitter Saturation Voltage vs. Temperature





## **Typical Electrical and Thermal Characteristics**



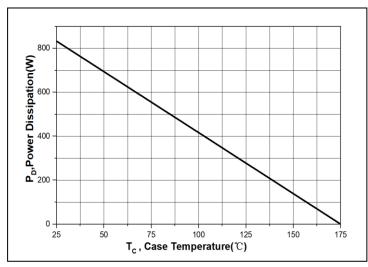
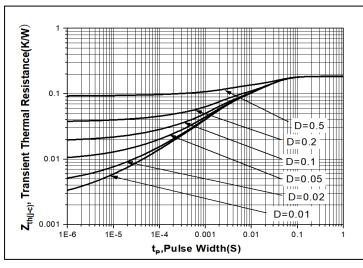


Figure7.Gate Threshold Voltage vs. Temperature

Figure8. Power Dissipation vs. Case Temperature



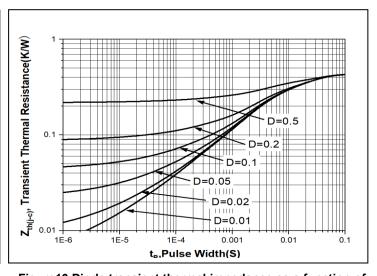


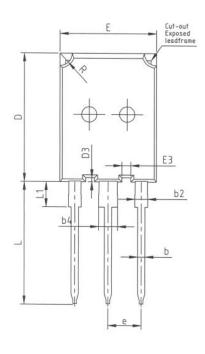
Figure 9. IGBT transient thermal resistance (D=  $t_p/T$ )

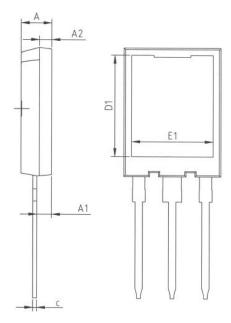
Figure 10. Diode transient thermal impedance as a function of pulse width ( $D=t_p/T$ )





## **Mechanical Data:**





COMMON DIMENSIONS

SYMBOL.		mm			
STRIDUL	MIN	NOM	MAX		
Α	A 4.80		5. 20		
A1	2. 21	2.41	2.61		
A2	1.85	2.00	2. 15		
b	1, 11	1.21	1.36		
b2	1.91	2.01	2. 21		
b4	2.91	3.01	3, 21		
С	0.50	0.61	0.75		
D	20.70	21.00	21.30		
D1	16. 25	16. 55	16.85		
D3	0.53	0.68	0.83		
Е	15.50	15.80	16.10		
E1	13, 10	13.30	13, 50		
E3	1.30	1.45	1.60		
е	5.44 (BSC)				
L	19, 62	19.92	20. 22		
L1	-	-	4.30		
R	1.85	2.00	2.15		





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